## Notice of References Cited Application/Control No. 10/785,072 Examiner Anna L. Verderame Applicatios/Patent Under Reexamination KAWAGUCHI, YUUICHI Anna L. Verderame Application/Control No. Applicant(s)/Patent Under Reexamination KAWAGUCHI, YUUICHI Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,352,656	03-2002	Kimura et al.	264/2.5
*	В	US-5,635,267	06-1997	Yamada et al.	428/64.4
*	С	US-5,244,755	09-1993	Benoist et al.	429/97
*	D	US-5,978,327	11-1999	Kuroda et al.	369/44.26
*	E	US-7,038,992	05-2006	Hori, Kazuhito	369/59.25
*	F	US-4,861,699	08-1989	Wijdenes et al.	430/321
*	G	US-5,330,880	07-1994	Horigome et al.	430/321
*	Н	US-6,352,656	03-2002	Kimura et al.	264/2.5
*	Ι	US-5,403,625	04-1995	Legierse et al.	427/437
*	J	US-7,026,029	04-2006	Lindholm et al.	428/64.1
*	К	US-5,119,359	06-1992	Miyagi et al.	369/112.05
*	L	US-5,173,313	12-1992	Sato et al.	425/183
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	jp09109276	10-1995	Japan	Kamiyama Kenichi Ichimur	
	0	JP06259815	09-1995	Japan	Matsushita Denki Sangyo K	
	Р					
	σ					
	R					
	s					
	Т				<u>:</u>	

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	υ	\				
	٧					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.